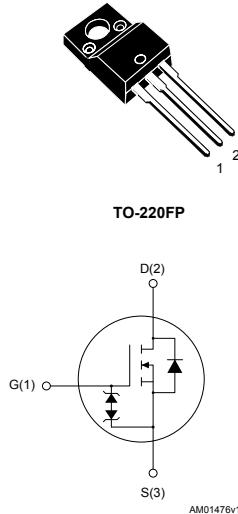


N-channel 600 V, 3.5 Ω typ., 2 A SuperMESH Power MOSFET in a TO-220FP package

Features



Order codes	V _{DS}	R _{DS(on)} max.	I _D
STF2HNK60Z	600 V	4.8 Ω	2 A

- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitance
- Zener-protected

Applications

- Switching applications

Description

This high-voltage device is a Zener-protected N-channel Power MOSFET developed using the SuperMESH technology by STMicroelectronics, an optimization of the well-established PowerMESH. In addition to a significant reduction in on-resistance, this device is designed to ensure a high level of dv/dt capability for the most demanding applications.



Product status link

[STF2HNK60Z](#)

Product summary

Order code	STF2HNK60Z
Marking	F2HNK60Z
Package	TO-220FP
Packing	Tube

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V_{GS}	Gate-source voltage	± 30	V
I_D	Drain current (continuous) at $T_C = 25^\circ\text{C}$	2.0	A
	Drain current (continuous) at $T_C = 100^\circ\text{C}$	1.26	
$I_{DM}^{(1)}$	Drain current (pulsed)	8	A
P_{TOT}	Total power dissipation at $T_C = 25^\circ\text{C}$	20	W
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink ($t = 1 \text{ s}, T_C = 25^\circ\text{C}$)	2.5	kV
ESD	Gate-source human body model ($R = 1.5 \text{ k}\Omega, C = 100 \text{ pF}$)	2	kV
$dv/dt^{(2)}$	Peak diode recovery voltage slope	4.5	V/ns
T_{STG}	Storage temperature range	-55 to 150	$^\circ\text{C}$
T_J	Operating junction temperature range		$^\circ\text{C}$

1. Pulse width limited by safe operating area.
2. $I_{SD} \leq 2 \text{ A}, di/dt \leq 200 \text{ A}/\mu\text{s}, V_{DS} (\text{peak}) \leq V_{(BR)DSS}, V_{DD} = 80\% V_{(BR)DSS}$.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	6.25	$^\circ\text{C}/\text{W}$
R_{thJA}	Thermal resistance, junction-to-ambient	62.5	$^\circ\text{C}/\text{W}$

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (t_p limited by T_J max)	2	A
E_{AS}	Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}, I_D = I_{AR}, V_{DD} = 50 \text{ V}$)	120	mJ

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}, T_C = 125^\circ\text{C}$ ⁽¹⁾			50	
I_{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 10	μA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 50 \mu\text{A}$	3	3.75	4.5	V
$R_{\text{DS(on)}}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 1 \text{ A}$		3.5	4.8	Ω

1. Specified By Design – Not tested in production.

Table 5. Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	280		pF
C_{oss}	Output capacitance		-	38		pF
C_{rss}	Reverse transfer capacitance		-	7		pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ to } 480 \text{ V}, V_{GS} = 0 \text{ V}$	-	30		pF
Q_g	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 2 \text{ A},$ $V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 14. Test circuit for gate charge behavior)	-	11	15 ⁽²⁾	nC
Q_{gs}	Gate-source charge		-	2.25		nC
Q_{gd}	Gate-drain charge		-	6		nC

1. $C_{oss \text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

2. Specified By Design – Not tested in production.

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 1 \text{ A},$	-	10	-	ns
t_r	Rise time	$R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	30	-	ns
$t_{d(off)}$	Turn-off delay time	(see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform)	-	23	-	ns
t_f	Fall time		-	50	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		2	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		8	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}, I_{SD} = 2 \text{ A}$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 2 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 20 \text{ V}$	-	178		ns
Q_{rr}	Reverse recovery charge	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	445		nC
I_{RRM}	Reverse recovery current		-	5		A
t_{rr}	Reverse recovery time	$I_{SD} = 2 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s},$	-	200		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 20 \text{ V}, T_J = 150 \text{ }^\circ\text{C}$	-	500		nC
I_{RRM}	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	5		A

1. Pulse width is limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

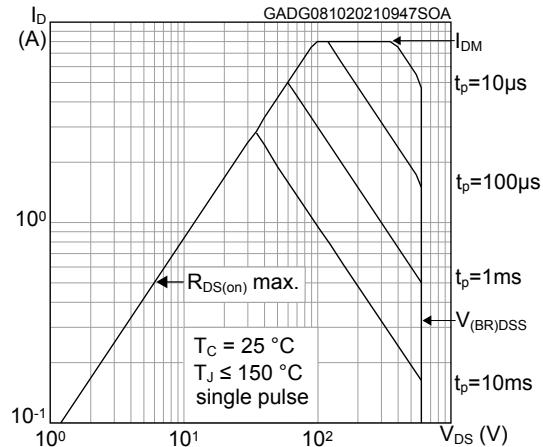
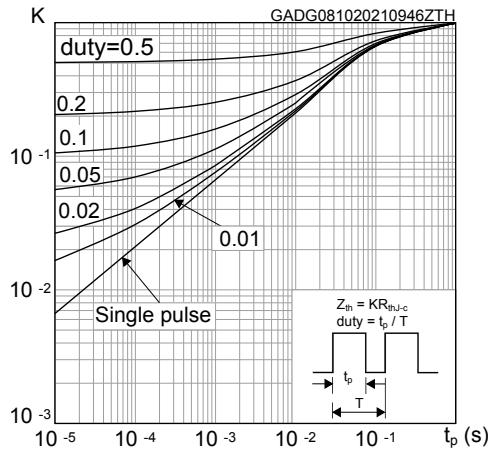
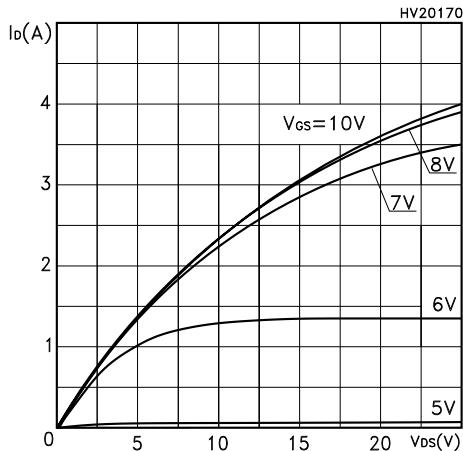
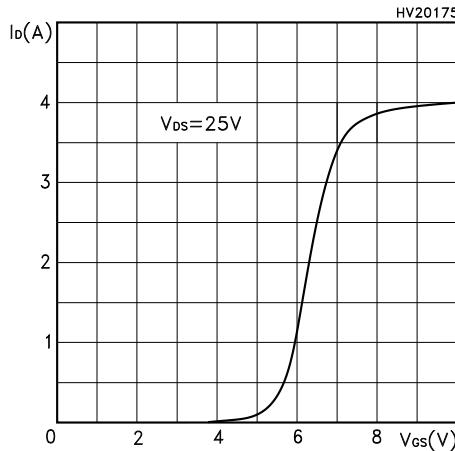
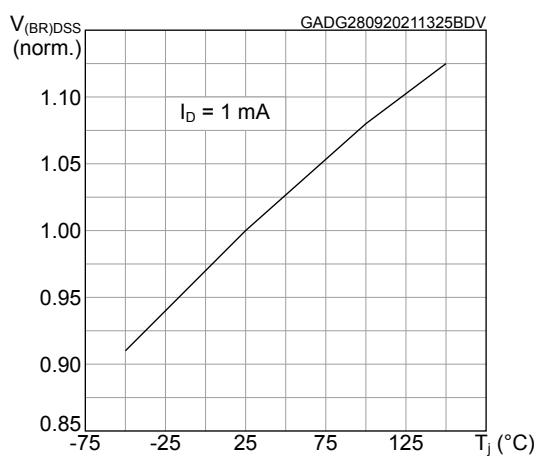
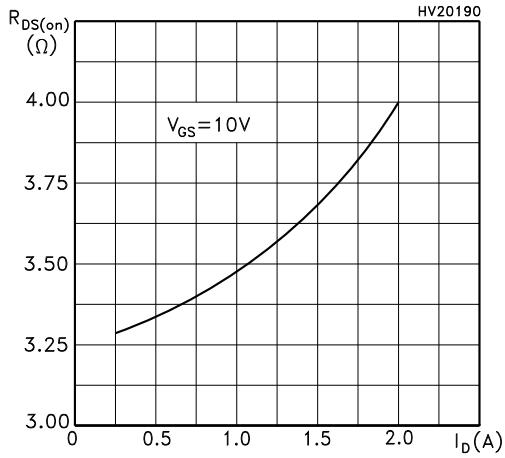
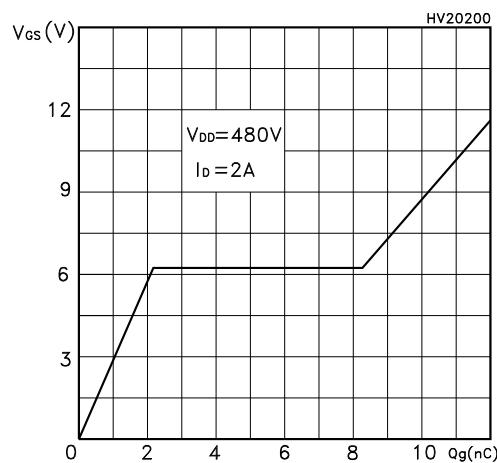
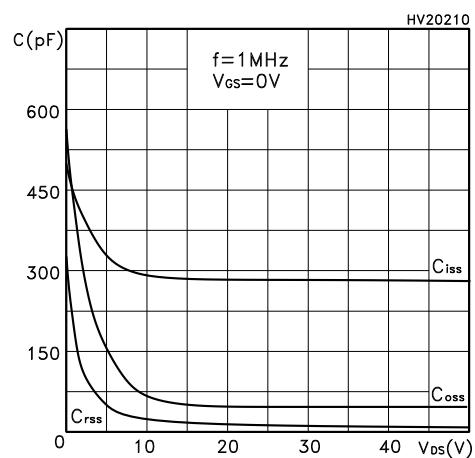
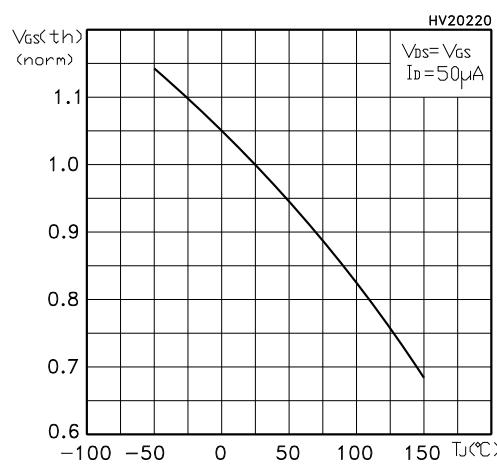
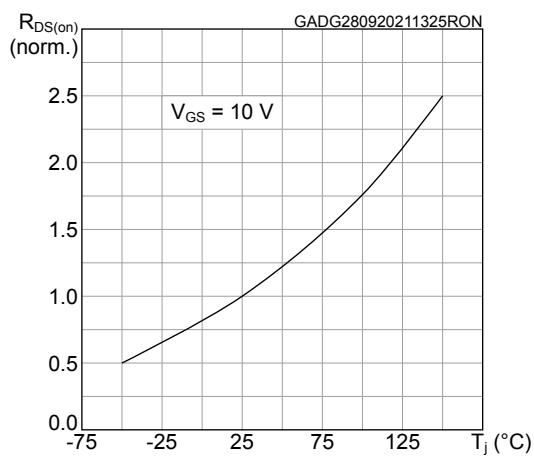
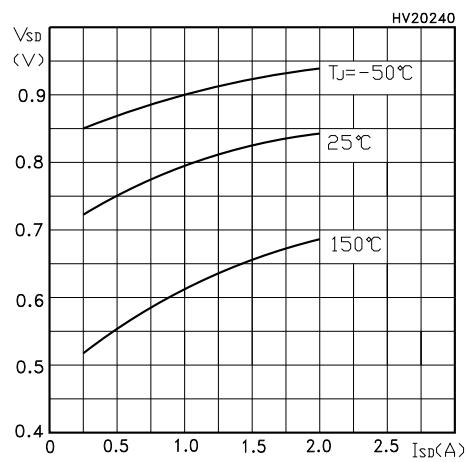
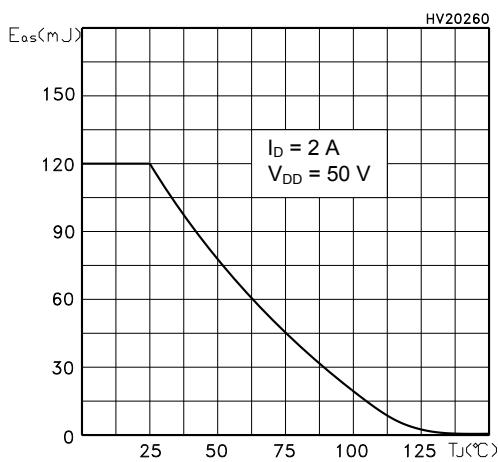
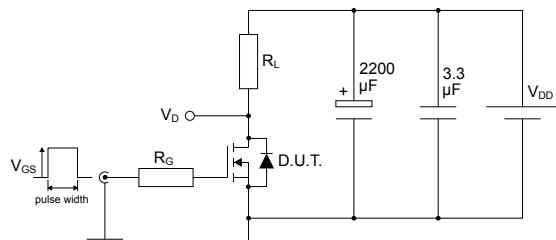
Figure 1. Safe operating area

Figure 2. Thermal impedance

Figure 3. Output characteristics

Figure 4. Transfer characteristics

Figure 5. Normalized $V_{(BR)DSS}$ vs temperature

Figure 6. Static drain-source on-resistance


Figure 7. Gate charge vs gate-source voltage

Figure 8. Capacitance variations

Figure 9. Normalized gate threshold voltage vs temperature

Figure 10. Normalized on-resistance vs temperature

Figure 11. Source-drain diode forward characteristics

Figure 12. Maximum avalanche energy vs temperature


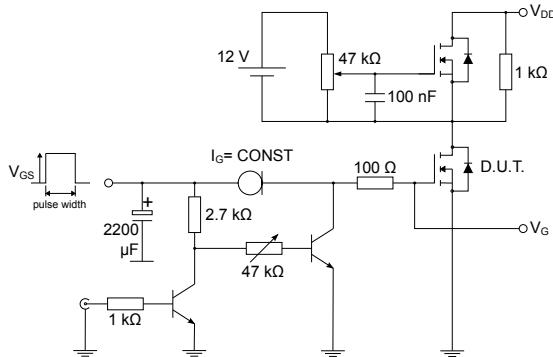
3 Test circuits

Figure 13. Test circuit for resistive load switching times



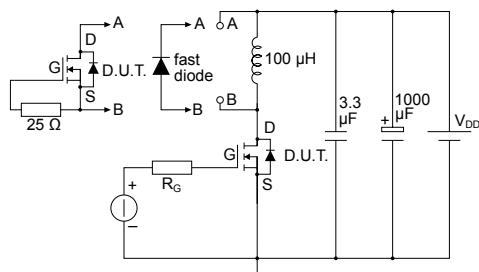
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Figure 14. Test circuit for gate charge behavior



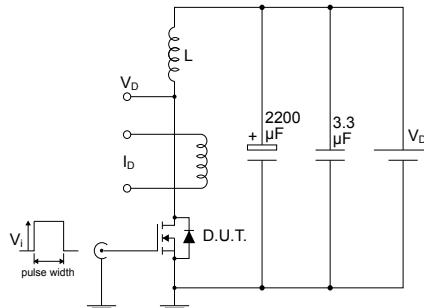
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Figure 15. Test circuit for inductive load switching and diode recovery times



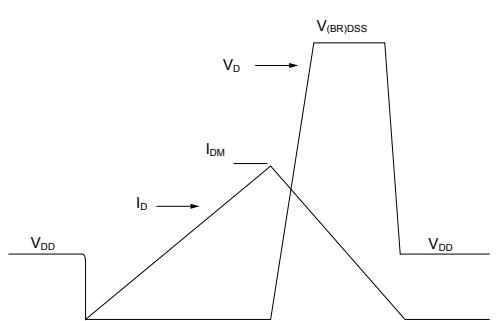
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Figure 16. Unclamped inductive load test circuit



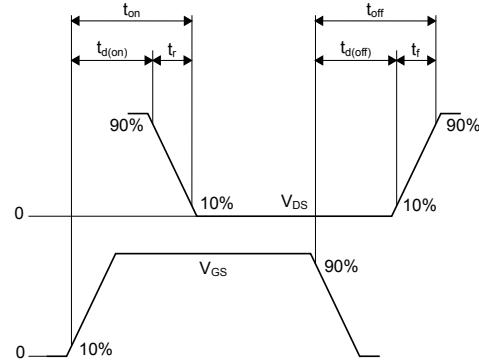
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Figure 17. Unclamped inductive waveform



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Figure 18. Switching time waveform



AM01473v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-220FP package information

Figure 19. TO-220FP package outline

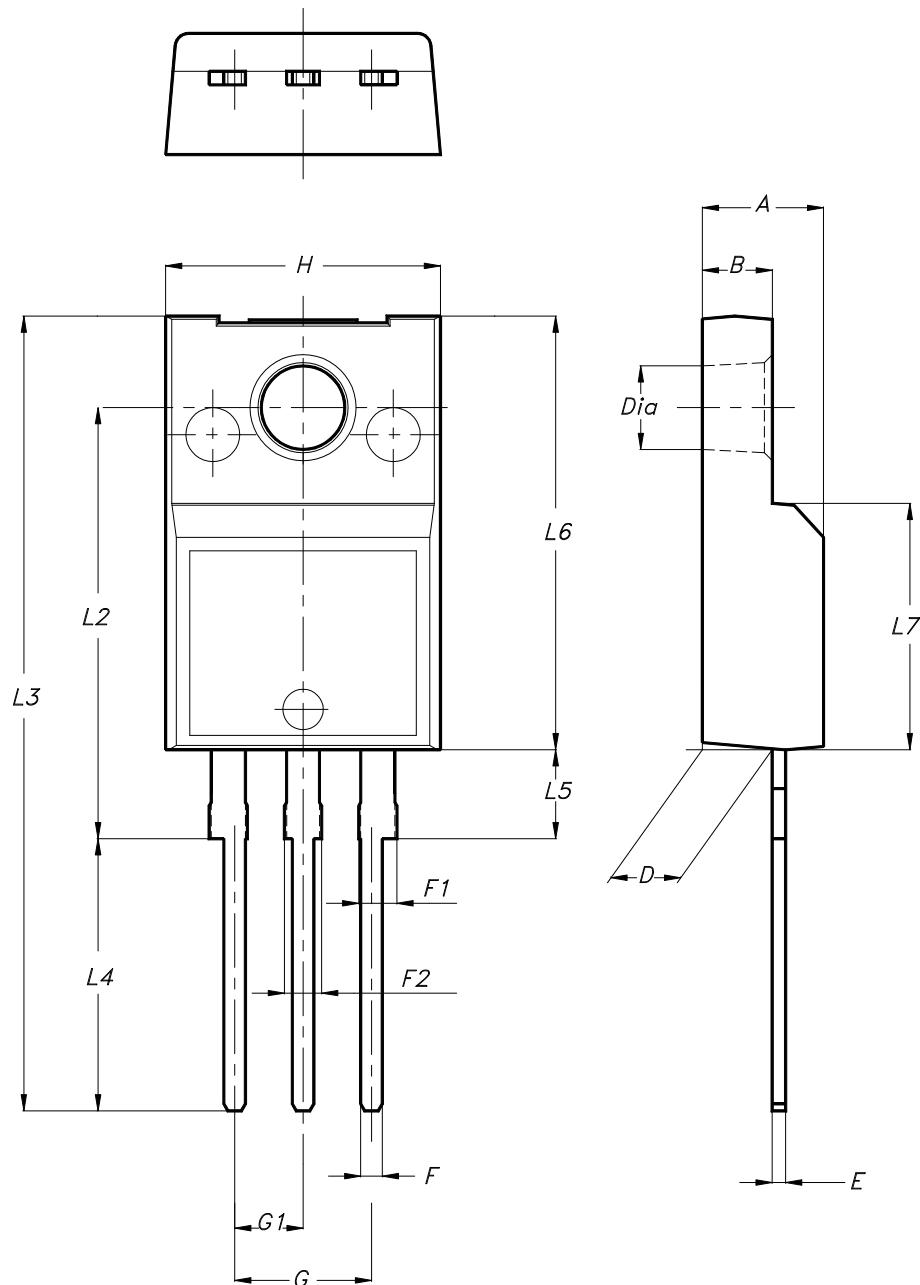


Table 8. TO-220FP package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
B	2.50		2.70
D	2.50		2.75
E	0.45		0.70
F	0.75		1.00
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.20
G1	2.40		2.70
H	10.00		10.40
L2		16.00	
L3	28.60		30.60
L4	9.80		10.60
L5	2.90		3.60
L6	15.90		16.40
L7	9.00		9.30
Dia	3.00		3.20

Revision history

Table 9. Document revision history

Date	Revision	Changes
12-Oct-2021	1	First release. Part number previously included in datasheet DS3646.

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